

Search Notes

Application/Control No.

10/783,172

Examiner

Evan Dzierzynski

Applicant(s)/Patent under
Reexamination

MAYER ET AL.

Art Unit

2875

SEARCHED

Class	Subclass	Date	Examiner
362	547	7/21/2005	EPD
	548	7/21/2005	EPD
	549	7/21/2005	EPD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search help from Peggy Niels	7/21/2005	EPD
Word search in EAST	7/21/2005	EPD
Updated search in EAST see attachment	11/30/2005	EPD